Se	arch	n Notes		

Application/Control No.	Applicant(s)/Paten Reexamination	t under
10/748,271	KIM ET AL.	
Examiner	Art Unit	
Joseph Nauven	2815	

	SEAD	CHED	
	JEAN	CHED	
Class	Subclass	Date	Examiner
257	59, 72	9/14/2006	JN
257	e29.117	9/14/2006	JN
257	e29.151	9/14/2006	JN
257	e29.273	9/14/2006	JN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
257	59,72	9/14/06	TN
257	E29.117	9/14/06	JW
257	E29.151	9/14/06	SN
257/E	29.273	9/14/06	JN

SEARCH I (INCLUDING SEAR	NOTES CH STRATEG	Y)
	DATE	EXMR
Search history in EAST	9/14/2006	JN
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